

14. TEST SETUP PHOTOGRAPHS

FCC ID: ZNFVS995		HAC (T-COIL) TEST REPORT		Reviewed by: Quality Manager
Filename: 0Y1607051224-R2.ZNF	Test Dates: 07/08/2016 - 07/15/2016	DUT Type: Portable Handset		Page 69 of 71

© 2016 PCTEST Engineering Laboratory, Inc.

REV 3.1.M
07/05/2016

© 2016 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from PCTEST Engineering Laboratory, Inc. If you have any questions about this international copyright or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact INFO@PCTESTLAB.COM.

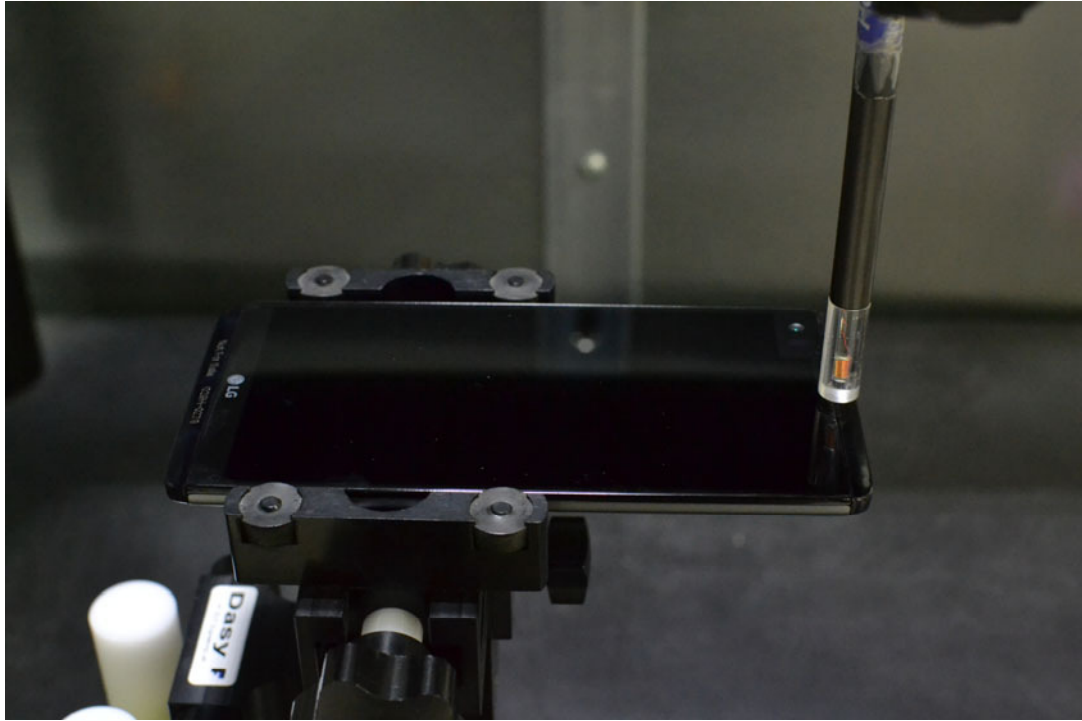


Figure 14-1
Test Setup for Wireless Device

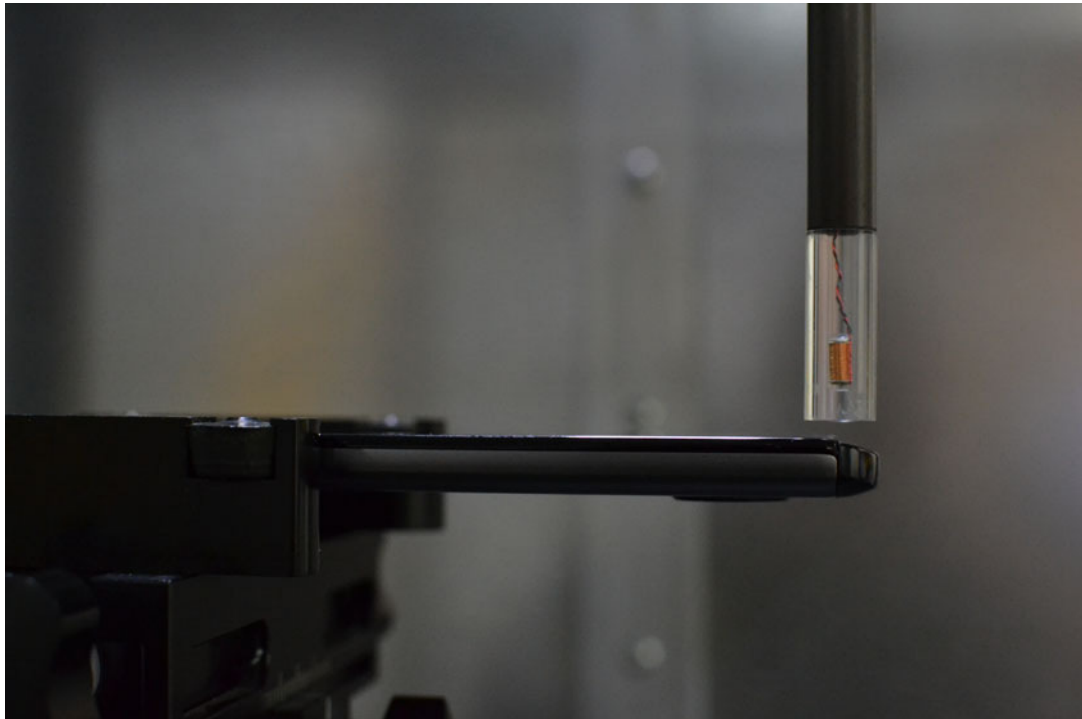


Figure 14-2
Test Setup for Wireless Device

FCC ID: ZNFVS995		HAC (T-COIL) TEST REPORT		Reviewed by: Quality Manager
Filename: 0Y1607051224-R2.ZNF	Test Dates: 07/08/2016 - 07/15/2016	DUT Type: Portable Handset		Page 70 of 71

© 2016 PCTEST Engineering Laboratory, Inc.

REV 3.1.M

07/05/2016

© 2016 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from PCTEST Engineering Laboratory, Inc. If you have any questions about this international copyright or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact INFO@PCTESTLAB.COM.

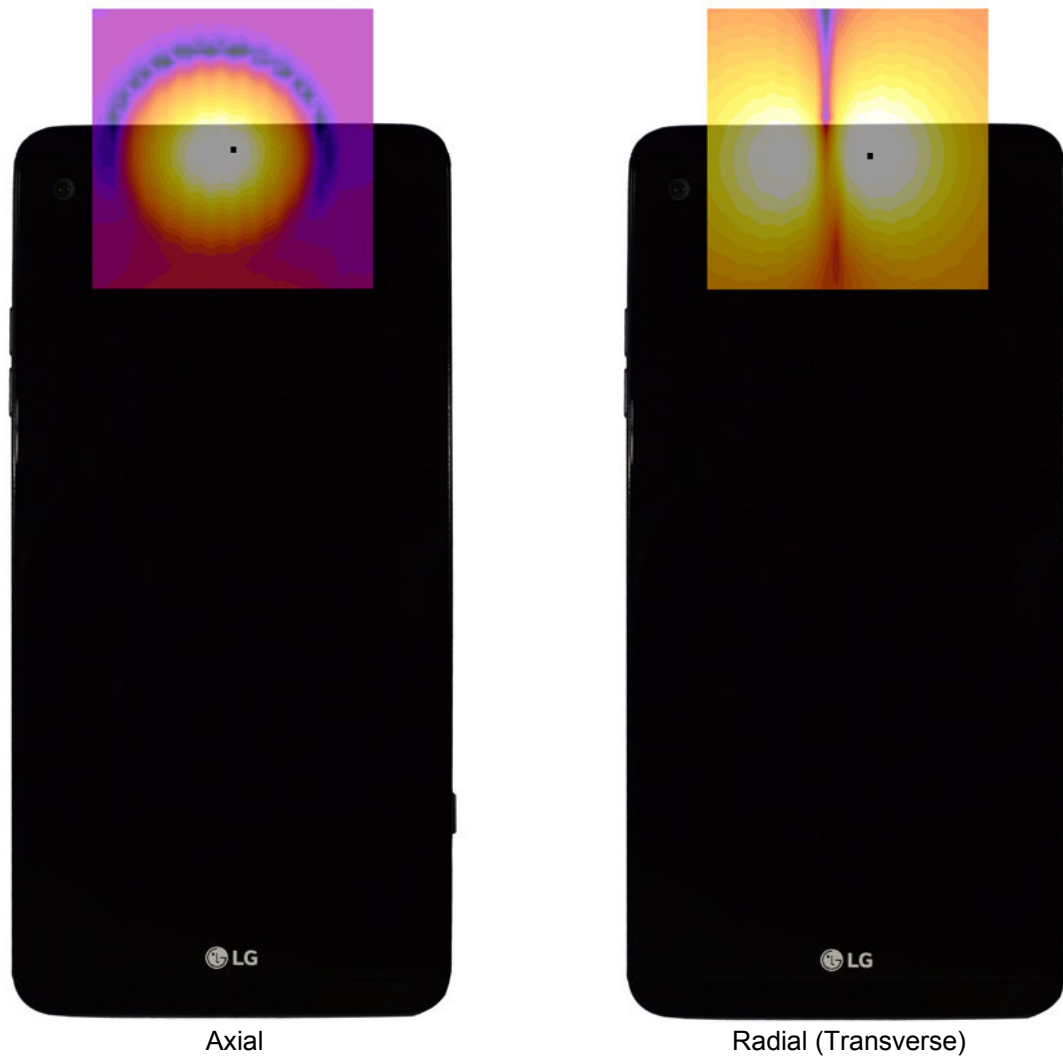


Figure 14-3
T-Coil Scan Overlay Magnetic Field Distributions

Note: Final measurement locations are indicated by a cursor on the contour plots.

FCC ID: ZNFVS995			HAC (T-COIL) TEST REPORT	 Reviewed by: Quality Manager
Filename: 0Y1607051224-R2.ZNF	Test Dates: 07/08/2016 - 07/15/2016	DUT Type: Portable Handset	Page 71 of 71	

© 2016 PCTEST Engineering Laboratory, Inc.

REV 3.1.M
07/05/2016

© 2016 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from PCTEST Engineering Laboratory, Inc. If you have any questions about this international copyright or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact INFO@PCTESTLAB.COM.